

Origin of magnetically dead layers in spinel ferrites $M\text{Fe}_2\text{O}_4$
grown on Al_2O_3 : Effects of post-deposition annealing studied by
XMCD

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Abstract

We study the electronic and magnetic states of as-grown and annealed $M\text{Fe}_2\text{O}_4(111)/\text{Al}_2\text{O}_3(111)$ ($M=\text{Co}, \text{Ni}$) thin films with various thicknesses grown on $\text{Si}(111)$ substrates with the $\gamma\text{-Al}_2\text{O}_3(111)$ buffer layers by using x-ray absorption spectroscopy (XAS) and x-ray magnetic circular dichroism (XMCD), to investigate magnetically dead layers in these films. Although the magnetically dead layers in the as-grown samples are formed near the interface with the Al_2O_3 buffer layer, we reveal that ferrimagnetic order is partially recovered by post-deposition annealing at 973 K for 48 hours in air. By analyzing the line shapes of the XAS and XMCD spectra, we conclude that, in the dead layers, there are a significant number of vacancies at the T_d sites of the spinel structure, which may be the microscopic origin of the degraded ferrimagnetic order in the $M\text{Fe}_2\text{O}_4$ thin films.

I. INTRODUCTION

Electronics have achieved great success by controlling the charge degree of freedom of electrons in semiconductors. By adding the spin degree of freedom to the existing electronics, a new field of electronics known as spintronics is being developed. Spintronics devices have several advantages over existing electronic devices, e.g., non-volatility, low energy consumption, high-speed, infinite endurance [1]. To establish next-generation electronics with semiconductor-based spintronics, injection of spin-polarized carriers into semiconductors should be realized at room temperature by utilizing a magnetic spin injector formed on the semiconductor. The spin filter is a promising technology to inject highly spin-polarized current into semiconductors. Insulating spinel-ferrite thin films are attracting high attention as a promising material for spin filters because they have the down-spin and up-spin conduction bands at different energies [the $3d\text{-}t_{2g}$ band of $\text{Fe}^{3+}(O_h)$ and the $3d\text{-}e$ band of $\text{Fe}^{3+}(T_d)$, as Fig. 1(a)] [2], and their Néel temperatures are much higher than room temperature (790 K for CoFe_2O_4 [3–5], and 850 K for NiFe_2O_4 [2, 6]). However, the experimentally obtained spin-filtering efficiency of ferrite-based tunnel barriers still remains considerably lower than the theoretical value of 100% [7–10]. In recent investigation, possible causes for this low spin-filtering efficiency have been proposed. One is that midgap impurity states are induced

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by structural and/or chemical defects [2, 4, 11]. For example, in CoFe_2O_4 , the presence of Co^{3+} degrades the spin filter due to the formation of up-spin states in the middle of the band gap. Another possibility is that layers with degraded magnetic properties are formed in the interfacial region, which is often called magnetically dead layers. They are well known for epitaxial Fe_3O_4 thin films grown on MgO substrates, and are thought to originate from antiphase boundaries and their antiferromagnetic interdomain exchange interaction [12–16]. In addition, a recent study on epitaxial Fe_3O_4 thin films grown on MgO substrates revealed that the first Fe_3O_4 monolayer lacks Fe^{3+} ions at the tetrahedral sites [17], resulting in a loss of the ferrimagnetic order due to missing superexchange paths.

In recent works [18–20], the magnetic properties of $M\text{Fe}_2\text{O}_4(111)/\text{Al}_2\text{O}_3(111)/\text{Si}(111)$ ($M=\text{Co}, \text{Ni}$) structures [21] were studied using the element-specific probes of x-ray absorption spectroscopy (XAS) and x-ray magnetic circular dichroism (XMCD). The authors revealed that the decrease of the inversion parameter y , defined by $y = [M_{1-y}\text{Fe}_y]_{T_d} / [\text{Fe}_{2-y}M_y]_{O_h}$, is correlated with the formation of magnetically dead layers. The inversion parameter y , which is equal to unity in the ideal inverse spinel, represents the regularity of the cation distribution in the spinel structure. It was found that the reduced thickness of the CoFe_2O_4 film leads to a significant reduction in both y and ferrimagnetic ordered moment. It was also found that NiFe_2O_4 has a larger y ($= 0.79\text{--}0.91$) than CoFe_2O_4 ($y = 0.54\text{--}0.75$), indicating that Ni has a higher O_h -site selectivity than Co. Considering that the cation distribution in $M\text{Fe}_2\text{O}_4$ can be modified by post-deposition annealing [5, 22], it is expected that annealing recovers the ferrimagnetic behavior of the interfacial region degraded by the formation of the magnetically dead layers. In the present study, we investigate the electronic and magnetic states of as-grown and annealed $M\text{Fe}_2\text{O}_4(111)/\text{Al}_2\text{O}_3(111)/\text{Si}(111)$ ($M=\text{Co}, \text{Ni}$) thin films using XAS and XMCD. We reveal that the degraded magnetic properties of the magnetically dead layer can be partially recovered by annealing through the redistribution of the cations. Furthermore, we find that there are a significant number of vacant T_d sites in the magnetically dead layers, and that such vacancies may degrade the ferrimagnetic order in the $M\text{Fe}_2\text{O}_4$ thin films.

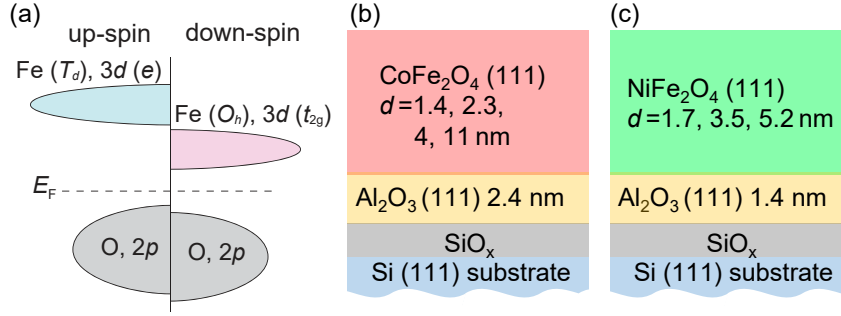


FIG. 1. Schematic description of the electronic structure of $M\text{Fe}_2\text{O}_4$ ($M = \text{Co}$ or Ni) and the sample structures. (a) Density of states of the valence-band top and conduction-band bottom for $M\text{Fe}_2\text{O}_4$, reproduced from Ref. 19. (b) Cross-sectional illustration of the $\text{CoFe}_2\text{O}_4(111)/\text{Al}_2\text{O}_3(111)/\text{Si}(111)$ structure, adapted from Ref. 18. (c) Cross-sectional illustration of the $\text{NiFe}_2\text{O}_4(111)/\text{Al}_2\text{O}_3(111)/\text{Si}(111)$ structure, adapted from Ref. 19.

II. EXPERIMENTAL METHODS

$\text{CoFe}_2\text{O}_4(111)$ and $\text{NiFe}_2\text{O}_4(111)$ thin films with various thicknesses were epitaxially grown on $\text{Al}_2\text{O}_3(111)$ buffer layers formed on $\text{Si}(111)$ substrates using the pulsed laser deposition (PLD) method. Schematic illustrations of the sample structures are shown in Figs. 1(b) and 1(c). 2.4 nm- and 1.4 nm-thick $\gamma\text{-Al}_2\text{O}_3(111)$ buffer layers were adopted for CoFe_2O_4 and NiFe_2O_4 thin films, respectively. The thicknesses of the films were $d = 1.4, 2.3, 4$, and 11 nm for CoFe_2O_4 , and $d = 1.7, 3.5$, and 5.2 nm for NiFe_2O_4 . In order to avoid charging up of the samples during the XAS and XMCD measurements, we used highly phosphorus-doped $\text{Si}(111)$ substrates with a low electrical resistivity $2 \text{ m}\Omega\text{cm}$. For the epitaxial growth of the $\gamma\text{-Al}_2\text{O}_3$ buffer layers on the Si substrates, we used solid-phase reaction of Al and SiO_2 . More detailed description of sample preparation and characterization are provided in Refs. 18 and 19. Some of the CoFe_2O_4 and NiFe_2O_4 thin films were annealed in order to redistribute the cations in the thin films, aiming at the recovery of the inversion parameter y . In order to suppress the oxidation of the Si substrate, the post-deposition annealing temperature was set to 973 K because the oxidation rate of Si rapidly increases particularly above 1073 K [23]. The films were annealed at 973 K for 48 hours in air. Since higher inversion parameters of CoFe_2O_4 have been reported in slowly cooled bulk crystals than in rapidly quenched ones [5], we set a slow cooling rate of 1 K/min down to 673 K and then the samples were naturally cooled down to room temperature.

XMCD measurements were performed at beamline BL-16A of Photon Factory, High Energy Accelerator Research Organization (KEK-PF). A magnetic field of 5 T was applied parallel to the incident x rays. The measurements were done at room temperature (~ 300 K). The absorption signals were detected in the total-electron-yield (TEY) mode. Since the probing depth in the TEY mode is a few nm [24, 25], the XAS and XMCD spectra of a few nm-thick films reflect the electronic and magnetic properties of the entire $M\text{Fe}_2\text{O}_4$ film including the magnetically dead layers near the spinel/ Al_2O_3 interface. By increasing the film thickness to $\gtrsim 5$ nm, the spectra more strongly reflect the signals away from the interface. The XMCD signals were collected by switching the photon helicity at every energy point.

In order to analyze the XAS and XMCD spectra quantitatively, we performed configuration-interaction (CI) cluster-model calculation [26]. The model is a good approximation for localized electron systems like the insulating spinel ferrites. In the present calculation, we used an Xtls version 8.5 program [27]. In choosing parameter values for the calculation, we adopted the following empirical rules : (1) The ratio between the on-site Coulomb energy between $3d$ electrons U_{dd} and the attractive $2p$ core hole- $3d$ electron Coulomb energy U_{dc} was fixed to $U_{dc}/U_{dd} \sim 1.3$ [28, 29]. (2) The ratio between Slater-Koster parameters ($pd\sigma$) and ($pd\pi$) was fixed to $(pd\sigma)/(pd\pi) = -2.17$ [30]. The hybridization strength between O $2p$ orbitals T_{pp} was fixed to 0.7 eV for the O_h site and 0 eV for the T_d site [27, 28]. The Slater integrals were set to be 80% of the Hartree-Fock values. Thus, the crystal-field splitting $10Dq$, the charge-transfer energy Δ , U_{dd} , and ($pd\sigma$) were treated as adjustable parameters. As for the Fe cations, the parameters were adjusted to reproduce all the measured Fe $L_{2,3}$ -edge spectra by the weighted sum of the calculated spectra for the $\text{Fe}^{2+}(O_h)$, $\text{Fe}^{3+}(T_d)$, and $\text{Fe}^{3+}(O_h)$ ions. Here, parameters for $\text{Fe}^{2+}(O_h)$ were adopted from the previous report on NiFe_2O_4 [19]. The adjusted parameter values are listed in Table I. As in our previous works [18, 19], we fitted the weighted sum of the calculated XAS and XMCD spectra for the $\text{Fe}^{2+}(O_h)$, $\text{Fe}^{3+}(T_d)$, and $\text{Fe}^{3+}(O_h)$ ions to the experimental ones. From this analysis, we obtained the relative amount of the three Fe components and thereby the inversion parameter y .

TABLE I. Parameter values for the CI cluster-model calculations used in the present study in units of eV. Parameters for $\text{Fe}^{2+}(O_h)$ were adopted from Ref. 19.

	Δ	$10Dq$	$(pd\sigma)$	U_{dd}
$\text{Fe}^{3+}(O_h)$	3.0	0.8	1.5	7.0
$\text{Fe}^{3+}(T_d)$	2.5	-0.5	1.8	6.0
$\text{Fe}^{2+}(O_h)$	6.5	0.9	1.4	6.0

III. RESULTS AND DISCUSSION

A. CoFe_2O_4 thin films

Figure 2 shows the Fe $L_{2,3}$ -edge XAS ($\mu^+ + \mu^-$) and XMCD ($\mu^+ - \mu^-$) spectra of the CoFe_2O_4 thin films with various thicknesses. Here, μ^+ (μ^-) denote the absorption coefficient for photon helicity parallel (antiparallel) to the majority-spin direction. Figure 2(a) shows that the Fe $L_{2,3}$ -edge XAS spectral line shapes do not change significantly by post-deposition annealing. In contrast, as shown in Fig. 2(b), the Fe $L_{2,3}$ -edge XMCD intensities of the annealed samples dramatically increase compared to the as-grown ones, particularly in thinner films ($d = 1.4$ and 2.3 nm). The increase of the XMCD intensities clearly demonstrates that the post-deposition annealing recovers the ferrimagnetic order in the magnetically dead layer of the as-grown films. The L_3 -edge XMCD spectra show characteristic three peaks denoted by **a**, **b**, and **c**. It is well established that the three peaks **a**, **b**, and **c** originate from the $\text{Fe}^{2+}(O_h)$, $\text{Fe}^{3+}(T_d)$, and $\text{Fe}^{3+}(O_h)$ ionic states, respectively [6, 9, 31, 32]. Therefore, one can discuss the Fe-ion distribution in spinel ferrites by estimating the intensities of these XMCD peaks. The spins of the $\text{Fe}^{3+}(T_d)$ ions are antiferromagnetically coupled with those at the O_h sites, resulting in the opposite signs between peak **b** and peaks **a/c**. Due to these distinct peak features, XMCD spectra are more sensitive to the cation distribution in spinel ferrites than XAS [9, 31, 32]. Figures 2(c) and 2(d) show comparison of the Fe L_3 -edge XMCD spectral line shapes of the as-grown and annealed CoFe_2O_4 films. The spectra have been normalized to the height of peak **c** to compare the spectral line shapes because the $L_{2,3}$ -edge XMCD intensities decrease with the reduction of the film thickness due to the magnetically dead layers. Figures 2(b) and 2(c) show that the $L_{2,3}$ -edge XMCD intensity decreases with

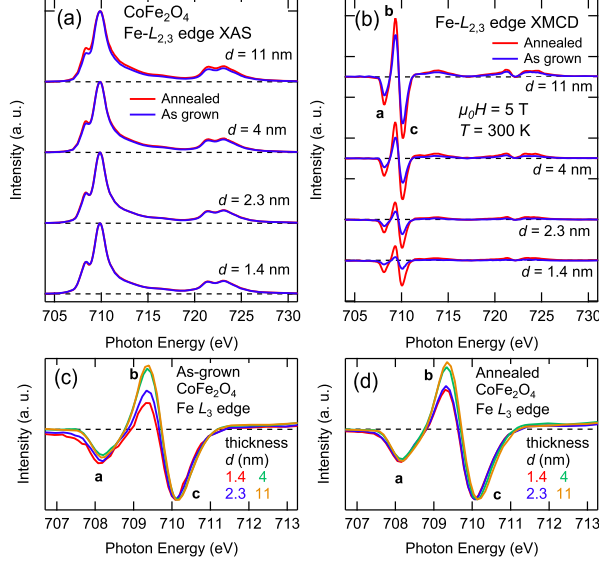


FIG. 2. Fe $L_{2,3}$ -edge XAS and XMCD spectra of the as-grown and annealed CoFe_2O_4 thin films with various thicknesses. (a), (b) Fe $L_{2,3}$ -edge XAS and XMCD spectra. In panel (a), a linear and a two-step backgrounds have been subtracted from the raw XAS spectra. The two-step backgrounds are composed of two arctangent functions located at the peak positions of L_3 and L_2 white lines. The height of the L_3 and L_2 steps are set to $\frac{2}{3}$ and $\frac{1}{3}$ of the average height around 740 eV, respectively. (c), (d) Magnified views of the Fe L_3 -edge XMCD spectra normalized to the height of peak **c**. The XMCD intensities decrease with decreasing thickness in the as-grown films [(b) and (c)], especially at peak **b**, reflecting the magnetically dead layers near the interface. Both the entire XMCD intensities and the relative intensity at peak **b** are partially recovered by post-deposition annealing particularly in thinner films [(b) and (d)].

the reduction of the thickness in the as-grown CoFe_2O_4 films and that the XMCD intensity at peak **b** decreases faster than peaks **a** and **c** as previously reported [18]. This indicates the reduction of the $\text{Fe}^{3+}(T_d)$ component of XMCD in magnetically dead layers near the interface. After post-deposition annealing, as shown in Fig. 2(b) and 2(d), both the entire XMCD intensities and the intensity at peak **b** are recovered simultaneously particularly in thinner films. This suggests that the Fe ions are redistributed and that ferrimagnetic order are simultaneously recovered near the interface by annealing.

To clarify the correlation between the cation redistribution and the recovery of the ferrimagnetic order, quantitative spectral line-shape analyses are necessary. We, therefore,

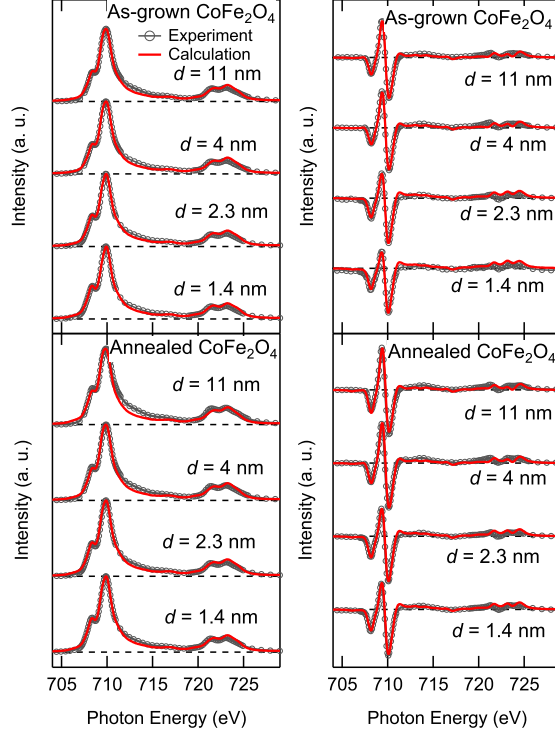


FIG. 3. Comparison between experimental and calculated XAS and XMCD spectra at the Fe $L_{2,3}$ edge of the as-grown and annealed CoFe_2O_4 thin films.

performed CI cluster-model calculation to reproduce the experimental XAS and XMCD spectra by the weighted sum of calculated $\text{Fe}^{2+}(\text{O}_h)$, $\text{Fe}^{3+}(\text{T}_d)$, and $\text{Fe}^{3+}(\text{O}_h)$ spectra using the parameters listed in Table I. Figure 3 shows comparison between the experimental and calculated XAS and XMCD spectra at the Fe $L_{2,3}$ edge. All the experimental spectra are well reproduced by the calculated spectra. Since the amount of the ion is proportional to the weight for each calculated XAS and XMCD spectra, the relative amount can be calculated by the spectral weight ratio. The relative amount deduced from fitting is plotted as functions of film thickness in Fig. 4(a), where the inversion parameter y is also deduced and plotted. One can see that y decreases with reducing thickness in the as-grown samples, and that y increases by the post-deposition annealing. The increase of y by annealing is more pronounced in the thinner samples, reflecting the redistribution of cations near the interface. Figure 4(b) shows the Fe L_3 -edge XMCD intensities of the as-grown and annealed films as functions of film thickness. The increase ratio of the Fe L_3 -edge XMCD intensity [$R \equiv \text{XMCD}(\text{annealed})/\text{XMCD}(\text{as grown})$] and the increase of the inversion parameter

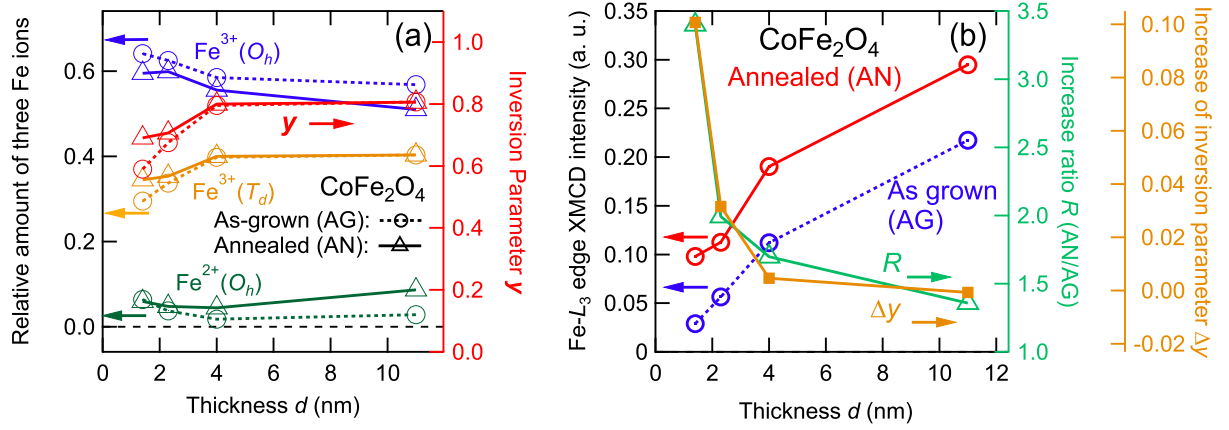


FIG. 4. Thickness dependences of the Fe-ion distribution and the L_3 -edge XMCD intensities for the as-grown and annealed CoFe₂O₄ thin films. (a) Relative amount of the Fe²⁺(O_h), Fe³⁺(T_d), and Fe³⁺(O_h) ions as functions of film thickness. The inversion parameter y is also plotted (right axis). Dashed lines and solid line indicate the as-grown and annealed samples, respectively. (b) Fe L_3 -edge XMCD intensity of the as-grown and annealed films. The increase of y by annealing (Δy) and the increase ratio of the XMCD intensity (R) are plotted on the right axes. The inversion parameter y decrease with reducing thickness in the as-grown samples [red dashed line in (a)], and y increases by annealing [red solid line in (a)]. Δy and R similarly decrease with the film thickness [green and brown lines in (b)], suggesting that the recovery of the magnetically dead layer is achieved by the redistribution of cations.

[$\Delta y \equiv y(\text{annealed}) - y(\text{as grown})$] are also shown for comparison. One can see similar thickness dependences between R and Δy , which suggests that the recovery of the magnetically dead layer is achieved by the redistribution of cations. Based on the above results and the definition of the inversion parameter y of spinel ferrites ($[\text{Co}_{1-y}\text{Fe}_y]_{T_d}[\text{Fe}_{2-y}\text{Co}_y]_{O_h}\text{O}_4$), one may think that the recovery of the magnetically dead layer by post-deposition annealing is caused by the reduction of the antisites near the interface, that is, the Co ions irregularly occupying the T_d sites are replaced by Fe ions after annealing. However, one also needs to take into account the cation vacancies at the T_d sites, as discussed below.

Figure 5 shows the Co $L_{2,3}$ -edge XAS and XMCD spectra for various film thicknesses and the effect of annealing on these spectra. In order to see the changes in the spectral line shapes, we show the Co- L_3 edge XMCD spectra normalized to the height of peak **e** in Figs.

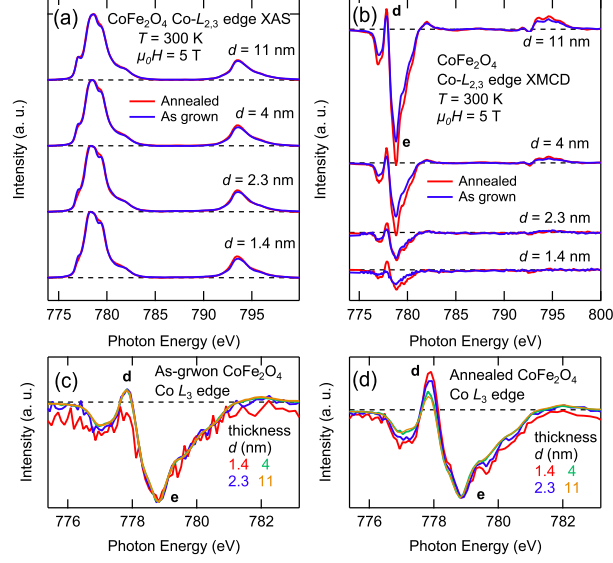


FIG. 5. Co $L_{2,3}$ -edge XAS and XMCD spectra of the as-grown and annealed CoFe_2O_4 thin films with various thicknesses. (a), (b) Co $L_{2,3}$ -edge XAS and XMCD spectra. (c), (d) Magnified views of Co L_3 -edge XMCD spectra normalized to the height of peak **e**. Since peak **d** originates from $\text{Co}^{2+}(T_d)$ ions [18], the increase of peak **d** indicates that the number of ferrimagnetically ordered $\text{Co}^{2+}(T_d)$ ions increase by post-deposition annealing.

5(c) and 5(d). One can see that the positive peak **d** increases by annealing, particularly in the thinner films. As described in the previous report [18], the positive peak at the Co L_3 edge originates from $\text{Co}^{2+}(T_d)$ ions. Therefore, the increase of peak **d** indicates the increase of the number of ferrimagnetically ordered $\text{Co}^{2+}(T_d)$ ions near the interface after annealing. The increase of the positive peak components could also explain the slight increase of the Co $L_{2,3}$ -edge XMCD intensities by annealing. Surprisingly, not only the number of $\text{Fe}^{3+}(T_d)$ ions but also that of ferrimagnetically ordered $\text{Co}^{2+}(T_d)$ ions increase by annealing. These results can be naturally understood if there are a significant number of vacant T_d sites near the interface of the as-grown CoFe_2O_4 thin films and that, after annealing, the vacancies are filled by Fe ions and possibly Co ions, too, diffused from the O_h sites (for details, see Section IV). We note that the inversion parameter y is defined based on the ideal spinel structure $([\text{Co}_{1-y}\text{Fe}_y]_{T_d}[\text{Fe}_{2-y}\text{Co}_y]_{O_h}\text{O}_4)$ and the vacant sites are not taken into account. The lowering of y may reflect not only the replacement of the Fe ion by the Co ion but also increase of the vacancies at the T_d and/or O_h sites.

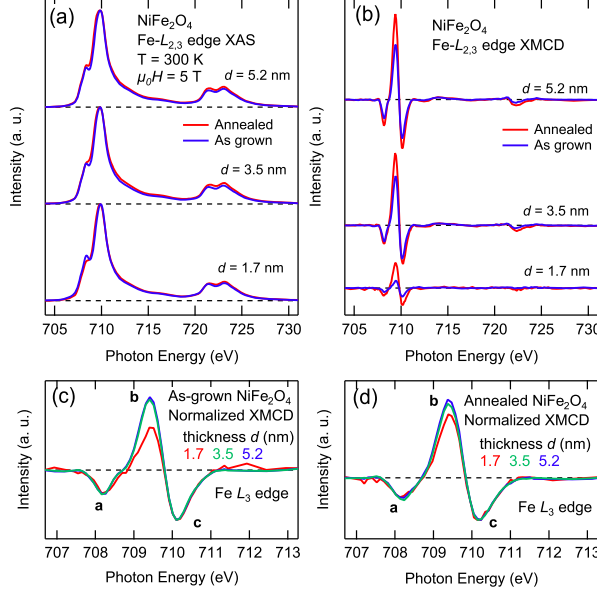


FIG. 6. Fe $L_{2,3}$ -edge XAS and XMCD spectra of the as-grown and annealed NiFe_2O_4 thin films with various thicknesses $d = 1.7, 3.5$, and 5.2 nm. (a), (b) Fe $L_{2,3}$ -edge XAS and XMCD spectra. (c), (d) Magnified views of the Fe L_3 -edge XMCD spectra normalized to the height of peak c. The changes in the spectra are similar to those of CoFe_2O_4 (Fig. 2).

B. NiFe_2O_4 thin films

Figure 6 shows the Fe $L_{2,3}$ -edge XAS and XMCD spectra of the as-grown and annealed NiFe_2O_4 thin films with thicknesses $d = 1.7, 3.5$, and 5.2 nm. Figure 7 shows the Ni $L_{2,3}$ -edge XAS and XMCD spectra of the NiFe_2O_4 films. The XMCD intensity of the 1.7 nm-thick film is extremely low compared to the others, indicating the dominant effect of magnetically dead layers. After annealing, the XMCD intensities increase for all the films. This clearly indicates that the magnetic order in the dead layers was significantly recovered by annealing also in the NiFe_2O_4 thin films.

To see the effect of annealing on the cation distribution, we compare the line shapes of normalized XMCD spectra at the Fe and Ni L_3 edges. Figures 6(c) and 6(d) show magnified views of the Fe L_3 -edges XMCD spectra normalized to the height of peak c. The spectral line shapes show that the positive peak b of the 1.7 nm-thick film significantly increases after annealing, indicating the increase of $\text{Fe}^{3+}(T_d)$ ions. On the other hand, the Ni-edge XMCD spectral line shapes, shown in Figs. 7(c) and 7(d), do not show any visible changes

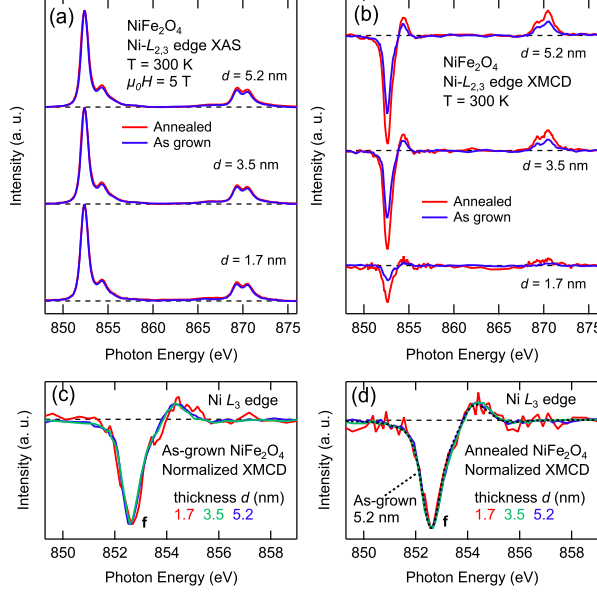


FIG. 7. Ni $L_{2,3}$ -edge XAS and XMCD spectra of the as-grown and annealed NiFe_2O_4 thin films with various thicknesses $d = 1.7, 3.5$, and 5.2 nm. The spectra of the as-grown films (blue lines) are adopted from Ref. 19. (a), (b) Ni $L_{2,3}$ -edge XAS and XMCD spectra. (c), (d) Magnified views of the Ni L_3 -edge XMCD spectra normalized to the height of peak **f** for the as-grown and annealed films. The normalized XMCD spectra of the 5.2-nm-thick as-grown film is also shown by a dashed black curve for comparison. In contrast to the Co $L_{2,3}$ -edge XMCD spectra shown in Fig. 5, spectral line shapes are not changed by annealing, reflecting the high O_h -site selectivity of the Ni^{2+} ion.

depending on the thickness and annealing. The XMCD spectra of the 5.2 nm-thick as-grown film are shown in Fig. 7(d) as a dashed black curve for comparison. One can clearly see that the spectral line shape remains the same after annealing. Because the Ni ion takes only the $\text{Ni}^{2+}(O_h)$ state, as reported in as-grown films [19], the unchanged spectral line shapes by annealing indicate that the Ni ions did not move to the T_d sites even after annealing, confirming the high O_h -site selectivity of the Ni^{2+} ion.

In order to quantitatively analyze the spectral line shapes of NiFe_2O_4 , as in the case of CoFe_2O_4 , we fitted the measured Fe $L_{2,3}$ -edge XAS and XMCD spectra using the weighted sum of the three calculated spectra of $\text{Fe}^{2+}(O_h)$, $\text{Fe}^{3+}(T_d)$, and $\text{Fe}^{3+}(O_h)$ ions. The parameters for the CI cluster model were the same as those for CoFe_2O_4 listed in Table I. Figure 8 shows the experimental and calculated Fe $L_{2,3}$ -edge XAS and XMCD spectra. The ex-

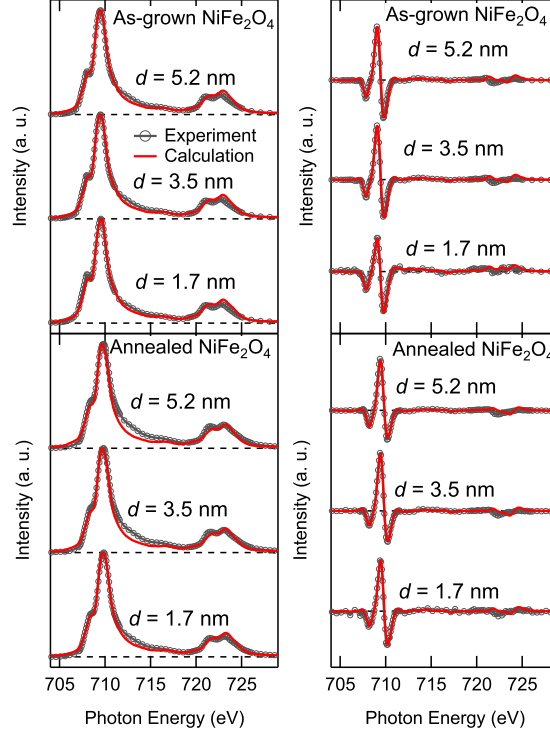


FIG. 8. Comparison between the experimental and calculated Fe $L_{2,3}$ -edge XAS and XMCD spectra of the as-grown and annealed NiFe_2O_4 thin films.

perimental spectra are well reproduced by the calculation. Using the weights obtained from the fitting, one can estimate the relative amount of the $\text{Fe}^{2+}(\text{O}_h)$, $\text{Fe}^{3+}(\text{T}_d)$, and $\text{Fe}^{3+}(\text{O}_h)$ ions in the as-grown and annealed NiFe_2O_4 thin films as shown in Fig. 9(a). One can see that, for the 1.7-nm-thick film, the ratio of the $\text{Fe}^{3+}(\text{T}_d)$ ions increases with post-deposition annealing, while that of the $\text{Fe}^{3+}(\text{O}_h)$ ions decreases. Thus, the inversion parameter y of the as-grown 1.7 nm-thick film is low compared to those of the thicker films, consistent with the XMCD result. The low y value of the 1.7 nm-thick film significantly increases to 0.96 after annealing (red dashed line). This means that NiFe_2O_4 thin films with almost no antisite defects are achieved after annealing. Figure 9(b) shows the Fe L_3 -edge XMCD intensities of the as-grown and annealed films as functions of film thickness. The increasing ratio of the Fe L_3 -edge XMCD intensity R and the increase of the inversion parameter Δy are also shown for comparison. Analogously to CoFe_2O_4 shown in Fig. 4(b), the similar thickness dependences between R and Δy suggest that the recovery of the magnetically dead layer is achieved by the redistribution of cations.

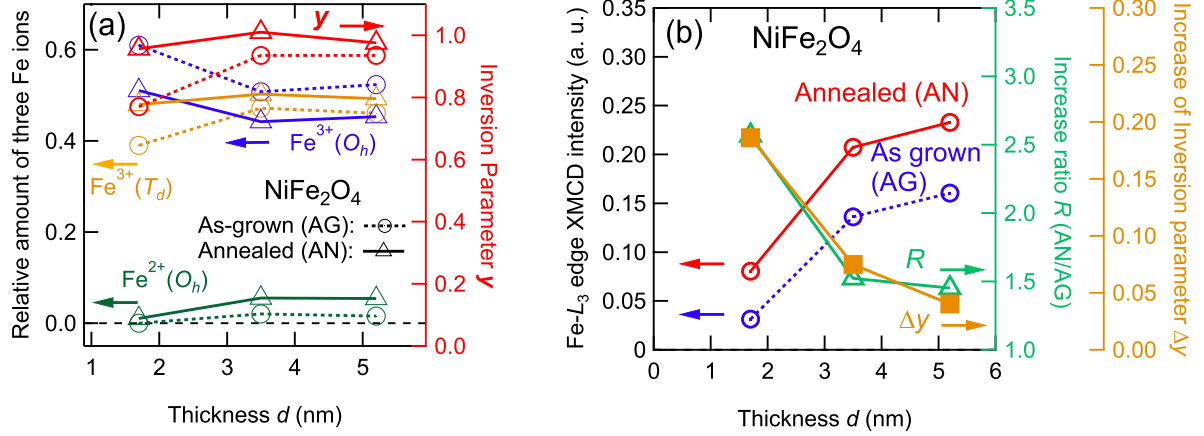


FIG. 9. Thickness dependences of the Fe-ion distribution and the L_3 -edge XMCD intensities for the as-grown and annealed NiFe₂O₄ thin films. (a) Relative amounts of the Fe²⁺(O_h), Fe³⁺(T_d), and Fe³⁺(O_h) ions in the as-grown and annealed NiFe₂O₄ thin films as functions of thickness. The inversion parameter y is also plotted on the right axis. Dashed lines with open circles and solid lines with open triangles indicate as-grown and annealed samples, respectively. (b) Fe L_3 -edge XMCD intensity of the as-grown and annealed films. The increase of y by annealing (Δy) and the increase ratio of XMCD intensities (R) are plotted on the right axes.

The ratio of Fe³⁺(T_d) to Fe³⁺(O_h) was about $\frac{2}{3}$ in the 1.7 nm-thick film before annealing. Considering that the Ni ions are located only at the O_h sites, one can estimate from this ratio that about $\frac{1}{3}$ of the T_d sites should be vacant in the as-grown 1.7 nm-thick film. As we shall discuss below, these vacancies at the T_d sites should have detrimental effects on the ferrimagnetic order in the spinel structure.

IV. DISCUSSION

We discuss the role of the cation vacant sites in the magnetically dead layers. As introduced above, based on the studies on Fe₃O₄ [12, 13, 16], it is believed that the magnetically dead layers in the spinel ferrites are caused by antiphase boundaries. However, as shown above, we find that there are a significant number of vacant T_d sites near the interface, and the transfer of the cations from the O_h to T_d sites caused by annealing significantly recovers the ferrimagnetic order. The antiferromagnetic superexchange interaction between

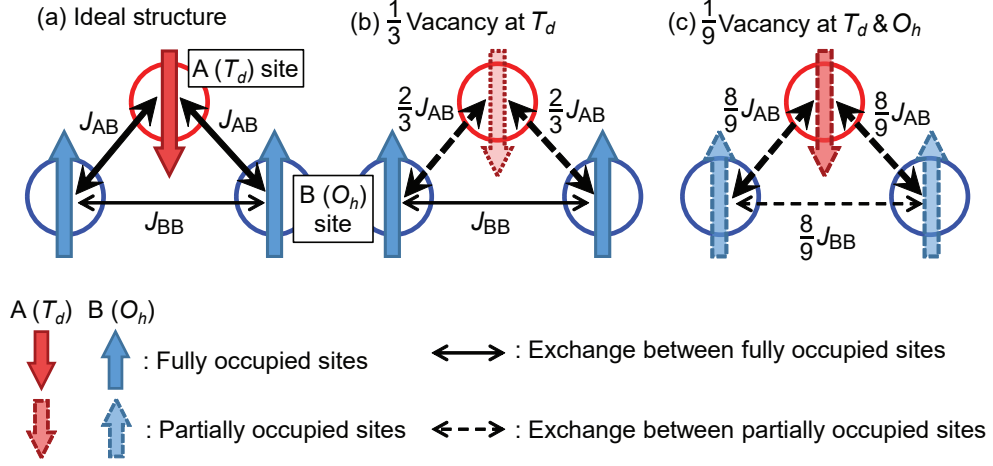


FIG. 10. Schematic pictures of exchange interaction between the T_d - and O_h -site ions. The T_d and O_h sites are labeled A and B , respectively.

TABLE II. Exchange interaction between transition metal ions in $M\text{Fe}_2\text{O}_4$ ($M=\text{Fe}, \text{Co}$) in units of K reproduced from Ref. 33. Suffixes A and B denotes the T_d and O_h sites, respectively. Note that the listed values include both the superexchange and direct exchange interactions. Positive and negative values correspond to ferromagnetic and antiferromagnetic interactions, respectively.

	$M = \text{Co} \quad M = \text{Ni}$	
J_{AB}	$\text{Fe}^{3+}-M^{2+}$	-22.7 -27.4
	$\text{Fe}^{3+}-\text{Fe}^{3+}$	-26 -30.7
J_{BB}	$M^{2+}-M^{2+}$	46.9 30.0
	$\text{Fe}^{3+}-M^{2+}$	-18.5 -2.7
	$\text{Fe}^{3+}-\text{Fe}^{3+}$	-7.5 -5.4

the T_d -site and O_h -site cations is the origin of the ferrimagnetic order in the spinel ferrites. Therefore, the lack of superexchange interaction due to the vacancies should significantly suppress the ferrimagnetism of magnetically dead layers. Here, we focus on how the vacant T_d sites affect the spin structures in the magnetically dead layers.

Figure 10(a) shows the exchange interaction between the cations at the O_h and T_d sites of the spinel structure. The values of the exchange interaction in $M\text{Fe}_2\text{O}_4$ ($M=\text{Co}, \text{Ni}$) deduced from magnetization measurements [33], which are denoted as J_{AB} and J_{BB} in Fig.

10, are listed in Table II in units of K. We note that suffix A (B) denotes the T_d (O_h) sites, and the ratio between $M^{2+}(O_h)$, $Fe^{3+}(T_d)$, and $Fe^{3+}(O_h)$ is 1 : 1 : 1 in an ideal inverse spinel structure. The large negative values of J_{AB} demonstrate the strong contributions of the T_d site to the ferrimagnetic order. As for the O_h - O_h interaction, J_{BB} , one can see large positive values for M^{2+} - M^{2+} interaction, and negative ones for Fe^{3+} - Fe^{3+} and Fe^{3+} - M^{2+} interactions. On average, O_h - O_h interactions are weakly ferromagnetic (+0.6 K for $CoFe_2O_4$ and +4.8 K for $NiFe_2O_4$) [34]. We note that the number of the O_h - T_d exchange pairs in an ideal spinel structure are 2.3 times larger than that of the O_h - O_h ones [13]. If $\frac{1}{3}$ of the T_d site is vacant as shown in Fig. 10(b), J_{AB} is weakened to $\frac{2}{3}$ of the ideal value, degrading the ferrimagnetic order. After annealing, some O_h -site ions move to T_d sites. For simplicity, assuming that the vacancies at the T_d sites are equally redistributed to all the T_d and O_h sites, as shown in Fig. 10(c), antiferromagnetic J_{AB} is recovered to $\frac{8}{9}$ of ideal value. Since the value and number of exchange interactions of J_{AB} are larger than that of J_{BB} , ferrimagnetic order should be stabilized. Although the actual numbers of the vacancies are still unclear, it can be concluded that vacancies at the O_h sites still preserve the ferrimagnetic order, whereas vacancies at the T_d sites significantly degrade the ferrimagnetic order. We should note that the above discussion ignores the effects of charge unbalance caused by the cation vacancies, that is, the effects of cation valence changes and possible oxygen vacancies. We speculate that there are oxygen vacancies [35] and/or that extra O_h sites [17] near the interface.

V. CONCLUSION

We have studied the electronic and magnetic states of the as-grown and annealed $CoFe_2O_4(111)$ and $NiFe_2O_4(111)$ thin films with various thicknesses grown on Si substrates with the γ - Al_2O_3 buffer layers. By analyzing the spectral line shapes using the CI cluster-model calculation, we have estimated the valences and site occupancies of Fe ions. We confirmed through the significant reduction of the XMCD intensities with decreasing film thickness that there are magnetically dead layers near the interface with γ - Al_2O_3 . As reported in the previous works [18, 19], the reduction of the inversion parameters was observed in the magnetically dead layers. By annealing the films for 48 hours in air to redistribute the cations, the XMCD intensity and inversion parameters significantly increase particularly in the thinner films. Furthermore, from comparison between the results on the as-grown and

annealed films, it is suggested that there are a significant number of vacant T_d sites in the magnetically dead layers. After the post-deposition annealing, the vacancies at the T_d sites are partially occupied by ions diffused from the O_h sites. Thus, we conclude that vacant T_d sites play an important role in the formation of the magnetically dead layers in spinel ferrites.

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